


<b>Search Notes</b> 	<b>Application/Control No.</b> 10576899	<b>Applicant(s)/Patent Under Reexamination</b> PAILA ET AL.
	<b>Examiner</b> MARCOS BATISTA	<b>Art Unit</b> 4134

SEARCHED			
Class	Subclass	Date	Examiner
		2/14/2008	mb
		2/14/2008	mb

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with TA - Yogesh Aggarwal	2/21/2008	mb
Consulted with Lun-Yi Lao	2/20/2008	mb
East Search	2/25/2008	mb

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner